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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

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Details	
Product Status	Obsolete
Number of LABs/CLBs	768
Number of Logic Elements/Cells	·
Total RAM Bits	·
Number of I/O	111
Number of Gates	12000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	144-LBGA
Supplier Device Package	144-FPBGA (13x13)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a54sx08a-2fgg144

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



General Description

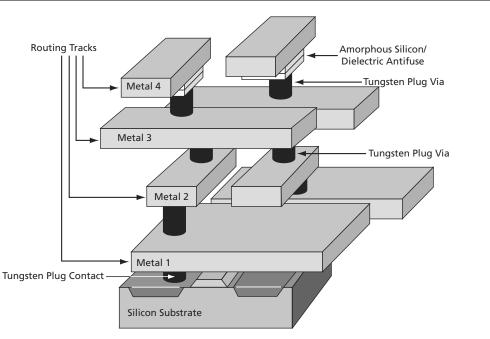
Introduction

The Actel SX-A family of FPGAs offers a cost-effective, single-chip solution for low-power, high-performance designs. Fabricated on 0.22 μm / 0.25 μm CMOS antifuse technology and with the support of 2.5 V, 3.3 V and 5 V I/Os, the SX-A is a versatile platform to integrate designs while significantly reducing time-to-market.

SX-A Family Architecture

The SX-A family's device architecture provides a unique approach to module organization and chip routing that satisfies performance requirements and delivers the most optimal register/logic mix for a wide variety of applications.

Interconnection between these logic modules is achieved using Actel's patented metal-to-metal programmable antifuse interconnect elements (Figure 1-1). The antifuses are normally open circuit and, when programmed, form a permanent low-impedance connection.



Note: The A54SX72A device has four layers of metal with the antifuse between Metal 3 and Metal 4. The A54SX08A, A54SX16A, and A54SX32A devices have three layers of metal with the antifuse between Metal 2 and Metal 3.

Figure 1-1 • SX-A Family Interconnect Elements



Probing Capabilities

SX-A devices also provide an internal probing capability that is accessed with the JTAG pins. The Silicon Explorer II diagnostic hardware is used to control the TDI, TCK, TMS, and TDO pins to select the desired nets for debugging. The user assigns the selected internal nets in Actel Silicon Explorer II software to the PRA/PRB output pins for observation. Silicon Explorer II automatically places the device into JTAG mode. However, probing functionality is only activated when the TRST pin is driven high or left floating, allowing the internal pull-up resistor to pull TRST High. If the TRST pin is held Low, the TAP controller remains in the Test-Logic-Reset state so no probing can be performed. However, the user must drive the TRST pin High or allow the internal pull-up resistor to pull TRST High. When selecting the **Reserve Probe Pin** box as shown in Figure 1-12 on page 1-9, direct the layout tool to reserve the PRA and PRB pins as dedicated outputs for probing. This **Reserve** option is merely a guideline. If the designer assigns user I/Os to the PRA and PRB pins and selects the **Reserve Probe Pin** option, Designer Layout will override the **Reserve Probe Pin** option and place the user I/Os on those pins.

To allow probing capabilities, the security fuse must not be programmed. Programming the security fuse disables the JTAG and probe circuitry. Table 1-9 summarizes the possible device configurations for probing once the device leaves the Test-Logic-Reset JTAG state.

JTAG Mode	TRST ¹	Security Fuse Programmed	PRA, PRB ²	TDI, TCK, TDO ²
Dedicated	Low	No	User I/O ³	JTAG Disabled
	High	No	Probe Circuit Outputs	JTAG I/O
Flexible	Low	No	User I/O ³	User I/O ³
	High	No	Probe Circuit Outputs	JTAG I/O
		Yes	Probe Circuit Secured	Probe Circuit Secured

Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved)

Notes:

1. If the TRST pin is not reserved, the device behaves according to TRST = High as described in the table.

2. Avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.

3. If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. Unused pins are automatically tristated by the Designer software.

Symbol	Parameter	Condition	Min.	Max.	Units
I _{OH(AC)}	Switching Current High	$0 < V_{OUT} \le 1.4^{-1}$	-44	-	mA
		$1.4 \le V_{OUT} < 2.4^{-1, 2}$	(-44 + (V _{OUT} - 1.4)/0.024)	_	mA
		3.1 < V _{OUT} < V _{CCI} ^{1, 3}	-	EQ 2-1 on page 2-5	-
	(Test Point)	V _{OUT} = 3.1 ³	-	-142	mA
I _{OL(AC)}	Switching Current Low	$V_{OUT} \ge 2.2^{-1}$	95	-	mA
		2.2 > V _{OUT} > 0.55 ¹	(V _{OUT} /0.023)	_	mA
		0.71 > V _{OUT} > 0 ^{1, 3}	-	EQ 2-2 on page 2-5	-
	(Test Point)	V _{OUT} = 0.71 ³	-	206	mA
I _{CL}	Low Clamp Current	$-5 < V_{IN} \le -1$	-25 + (V _{IN} + 1)/0.015	-	mA
slew _R	Output Rise Slew Rate	0.4 V to 2.4 V load 4	1	5	V/ns
slew _F	Output Fall Slew Rate	2.4 V to 0.4 V load 4	1	5	V/ns

Table 2-8 • AC Specifications (5 V PCI Operation)

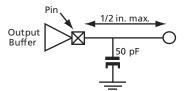
Notes:

1. Refer to the V/I curves in Figure 2-1 on page 2-5. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.

2. Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.

3. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 2-1 on page 2-5. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.

4. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.



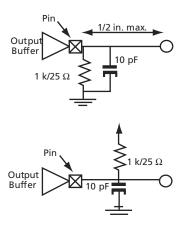
Symbol	Parameter	Condition	Min.	Max.	Units
I _{OH(AC)}	Switching Current High	$0 < V_{OUT} \le 0.3 V_{CCI}$ ¹	-12V _{CCI}	-	mA
		$0.3V_{CCI} \le V_{OUT} < 0.9V_{CCI}$ ¹	(–17.1(V _{CCI} – V _{OUT}))	-	mA
		0.7V _{CCI} < V _{OUT} < V _{CCI} ^{1, 2}	-	EQ 2-3 on page 2-7	_
	(Test Point)	$V_{OUT} = 0.7 V_{CC}^2$	_	-32V _{CCI}	mA
I _{OL(AC)}	Switching Current Low	$V_{CCI} > V_{OUT} \ge 0.6 V_{CCI}^{1}$	$V_{CCI} > V_{OUT} \ge 0.6 V_{CCI}^{1}$ 16 V_{CCI}		
		$0.6V_{CCI} > V_{OUT} > 0.1V_{CCI}^{1}$	(26.7V _{OUT})	-	mA
		0.18V _{CCI} > V _{OUT} > 0 ^{1, 2}	-	EQ 2-4 on page 2-7	_
	(Test Point)	$V_{OUT} = 0.18 V_{CC}^2$	-	38V _{CCI}	mA
I _{CL}	Low Clamp Current	$-3 < V_{IN} \le -1$	–25 + (V _{IN} + 1)/0.015	-	mA
I _{CH}	High Clamp Current	$V_{CCI} + 4 > V_{IN} \ge V_{CCI} + 1$	25 + (V _{IN} – V _{CCI} – 1)/0.015	-	mA
slew _R	Output Rise Slew Rate	0.2V _{CCI} - 0.6V _{CCI} load ³	1	4	V/ns
slew _F	Output Fall Slew Rate	0.6V _{CCI} - 0.2V _{CCI} load ³	1	4	V/ns

Table 2-10 • AC Specifications (3.3 V PCI Operation)

Notes:

1. Refer to the V/I curves in Figure 2-2 on page 2-7. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.

- 2. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (C and D) are provided with the respective diagrams in Figure 2-2 on page 2-7. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
- 3. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per the latest revision of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is required (the maximum is no longer simply a guideline). Rise slew rate does not apply to open drain outputs.



Theta-JA

Junction-to-ambient thermal resistance (θ_{JA}) is determined under standard conditions specified by JESD-51 series but has little relevance in actual performance of the product in real application. It should be employed with caution but is useful for comparing the thermal performance of one package to another.

A sample calculation to estimate the absolute maximum power dissipation allowed (worst case) for a 329-pin PBGA package at still air is as follows. i.e.:

$$\theta_{JA} = 17.1^{\circ}$$
C/W is taken from Table 2-12 on page 2-11

 $T_A = 125$ °C is the maximum limit of ambient (from the datasheet)

Max. Allowed Power =
$$\frac{\text{Max Junction Temp - Max. Ambient Temp}}{\theta_{JA}} = \frac{150^{\circ}\text{C} - 125^{\circ}\text{C}}{17.1^{\circ}\text{C/W}} = 1.46 \text{ W}$$

EQ 2-11

The device's power consumption must be lower than the calculated maximum power dissipation by the package.

The power consumption of a device can be calculated using the Actel power calculator. If the power consumption is higher than the device's maximum allowable power dissipation, then a heat sink can be attached on top of the case or the airflow inside the system must be increased.

Theta-JC

Junction-to-case thermal resistance (θ_{JC}) measures the ability of a device to dissipate heat from the surface of the chip to the top or bottom surface of the package. It is applicable for packages used with external heat sinks and only applies to situations where all or nearly all of the heat is dissipated through the surface in consideration. If the power consumption is higher than the calculated maximum power dissipation of the package, then a heat sink is required.

Calculation for Heat Sink

For example, in a design implemented in a FG484 package, the power consumption value using the power calculator is 3.00 W. The user-dependent data T_J and T_A are given as follows:

$$T_J = 110^{\circ}C$$

 $T_A = 70^{\circ}C$

From the datasheet:

 $\theta_{JA} = 18.0^{\circ}C/W$ $\theta_{JC} = 3.2^{\circ}C/W$

$$P = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{110^{\circ}\text{C} - 70^{\circ}\text{C}}{18.0^{\circ}\text{C/W}} = 2.22 \text{ W}$$

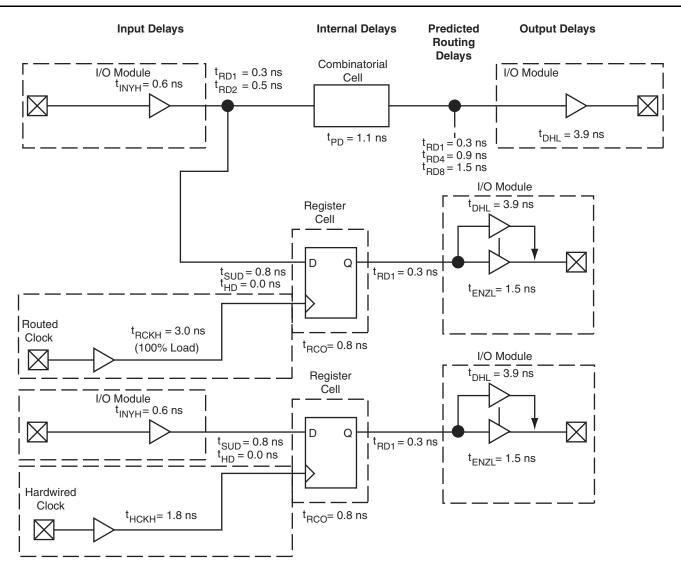
EQ 2-12

The 2.22 W power is less than then required 3.00 W; therefore, the design requires a heat sink or the airflow where the device is mounted should be increased. The design's junction-to-air thermal resistance requirement can be estimated by:

$$\theta_{JA} = \frac{Max Junction Temp - Max. Ambient Temp}{P} = \frac{110^{\circ}C - 70^{\circ}C}{3.00 W} = 13.33^{\circ}C/W$$

EQ 2-13

SX-A Timing Model



Note: *Values shown for A54SX72A, –2, worst-case commercial conditions at 5 V PCI with standard place-and-route. Figure 2-3 • SX-A Timing Model

Sample Path Calculations

Hardwired Clock

External Setup	=	(t _{INYH} + t _{RD1} + t _{SUD}) – t _{HCKH}
	=	0.6 + 0.3 + 0.8 - 1.8 = - 0.1 ns
Clock-to-Out (Pad-to-Pad)	=	t _{HCKH} + t _{RCO} + t _{RD1} + t _{DHL}
	=	1.8 + 0.8 + 0.3 + 3.9 = 6.8 ns

Routed Clock

External Setup	= (t _{INYH} + t _{RD1} + t _{SUD}) – t _{RCKH}
	= 0.6 + 0.3 + 0.8 - 3.0 = -1.3 ns
Clock-to-Out (Pad-to-Pad	$I) = t_{RCKH} + t_{RCO} + t_{RD1} + t_{DHL}$
	= 3.0 + 0.8 + 0.3 + 3.9 = 8.0 ns

Table 2-25 A54SX16A Timing Characteristics

-				
(Worst-Case Commercial	Conditions V	2 2 5 1 / 1	1 2 2 E V	T 70°C)
(worst-case commercial	Conditions v	$r_A = Z.ZO V.V$	$V_{CCI} = Z.ZO V_{C}$	$I_1 = 10^{-1}$
(.CA =-=		- , - <i>-</i> ,

		-3 Speed ¹	-2 S	peed	–1 Sp	beed	Std.	Speed	–F S	peed	
Parameter	Description	Min. Max	. Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
2.5 V LVCM	OS Output Module Timing ^{2, 3}	•									
t _{DLH}	Data-to-Pad Low to High	3.4		3.9		4.5		5.2		7.3	ns
t _{DHL}	Data-to-Pad High to Low	2.6		3.0		3.3		3.9		5.5	ns
t _{DHLS}	Data-to-Pad High to Low—low slew	11.6		13.4		15.2		17.9		25.0	ns
t _{ENZL}	Enable-to-Pad, Z to L	2.4		2.8		3.2		3.7		5.2	ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew	11.8		13.7		15.5		18.2		25.5	ns
t _{ENZH}	Enable-to-Pad, Z to H	3.4		3.9		4.5		5.2		7.3	ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.1		2.5		2.8		3.3		4.7	ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.6		3.0		3.3		3.9		5.5	ns
d_{TLH}^{4}	Delta Low to High	0.03		0.037		0.043		0.051		0.071	ns/pF
d_{THL}^4	Delta High to Low	0.01	7	0.017		0.023		0.023		0.037	ns/pF
${\sf d_{THLS}}^4$	Delta High to Low—low slew	0.05	7	0.06		0.071		0.086		0.117	ns/pF

Note:

1. All –3 speed grades have been discontinued.

2. Delays based on 35 pF loading.

3. The equivalent IO Attribute settings for 2.5 V LVCMOS is 2.5 V LVTTL in the software.

4. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = $(0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$ where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL]HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-27 A54SX16A Timing Characteristics

(Worst-Case Commercial Conditions V _{CCA}	$x = 2.25 \text{ V}, \text{ V}_{\text{CCI}} = 4.75 \text{ V}, \text{ T}_{\text{J}} = 70^{\circ}\text{C}$
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		-3 Speed ¹		-2 S	peed	-1 S	peed	Std. Speed		d –F Speed			
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units	
5 V PCI Out	5 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High		2.2		2.5		2.8		3.3		4.6	ns	
t _{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns	
t _{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0		2.8	ns	
t _{ENZH}	Enable-to-Pad, Z to H		2.2		2.5		2.8		3.3		4.6	ns	
t _{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns	
t _{ENHZ}	Enable-to-Pad, H to Z		2.8		3.2		3.6		4.2		5.9	ns	
d_{TLH}^{3}	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF	
d_{THL}^{3}	Delta High to Low		0.026		0.03		0.032		0.04		0.052	ns/pF	
5 V TTL Out	put Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High		2.2		2.5		2.8		3.3		4.6	ns	
t _{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns	
t _{DHLS}	Data-to-Pad High to Low—low slew		6.7		7.7		8.7		10.2		14.3	ns	
t _{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns	
t _{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns	
t _{ENZH}	Enable-to-Pad, Z to H		1.9		2.2		2.5		2.9		4.1	ns	
t _{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns	
t _{ENHZ}	Enable-to-Pad, H to Z		2.5		2.9		3.3		3.9		5.4	ns	
d _{TLH} ³	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF	
d _{THL} ³	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF	
d _{THLS} ³	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF	

Notes:

1. All –3 speed grades have been discontinued.

2. Delays based on 50 pF loading.

3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = (0.1* V_{CCI} - 0.9* V_{CCI} / (C_{load} * $d_{T[LH|HL|HLS]}$) where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-28 A545X32A Timing Characteristics (Continued)

		-3 Sp	beed ¹	-2 Sp	beed	-1 S	peed	Std. 9	Speed	–F Sp	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{INYH}	Input Data Pad to Y High 5 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t _{INYL}	Input Data Pad to Y Low 5 V PCI		0.9		1.1		1.2		1.4		1.9	ns
t _{INYH}	Input Data Pad to Y High 5 V TTL		0.9		1.1		1.2		1.4		1.9	ns
t _{INYL}	Input Data Pad to Y Low 5 V TTL		1.4		1.6		1.8		2.1		2.9	ns
Input Modu	le Predicted Routing Delays ³											
t _{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t _{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t _{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t _{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1		1.4	ns
t _{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t _{IRD12}	FO = 12 Routing Delay		1.7		2		2.2		2.6		3.6	ns

(Worst-Case Commercial Conditions, $V_{CCA} = 2.25 \text{ V}_{CCI} = 3.0 \text{ V}, T_J = 70^{\circ}\text{C}$)

Notes:

1. All –3 speed grades have been discontinued.

2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-30 • A54SX32A Timing Characteristics

(Worst-Case Commercial Conditions	V _{CCA} = 2.25 V, V _{CCI} = 3.0 V, T _J = 70°C)
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		-3 S	beed*	-2 S	peed	-1 S	peed	Std. Speed		d –F Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated	(Hardwired) Array Clock Netwo	rks										<u> </u>
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{HPVVL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns
t _{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		357		313		278		238		172	MHz
Routed Arr	ay Clock Networks											
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.6	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.4		2.7		3.2		4.5	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.3		2.7		3.1		3.6		5	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.5		2.9		3.4		4.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.4		2.8		3.2		3.7		5.2	ns
t _{rckl}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.8		3.1		3.7		5.1	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.9		1.0		1.2		1.4		1.9	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.4		1.9	ns

Note: *All –3 speed grades have been discontinued.

Table 2-32 A54SX32A Timing Characteristics

		-3 Sp	eed ¹	-2 S	peed	–1 S	peed	Std. 9	5peed	–F Sj	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
2.5 V LVCM	OS Output Module Timing ^{2,3}											
t _{DLH}	Data-to-Pad Low to High		3.3		3.8		4.2		5.0		7.0	ns
t _{DHL}	Data-to-Pad High to Low		2.5		2.9		3.2		3.8		5.3	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		11.1		12.8		14.5		17.0		23.8	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.4		2.8		3.2		3.7		5.2	ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew		11.8		13.7		15.5		18.2		25.5	ns
t _{ENZH}	Enable-to-Pad, Z to H		3.3		3.8		4.2		5.0		7.0	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.1		2.5		2.8		3.3		4.7	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.5		2.9		3.2		3.8		5.3	ns
d_{TLH}^{4}	Delta Low to High		0.031		0.037		0.043		0.051		0.071	ns/pF
d_{THL}^4	Delta High to Low		0.017		0.017		0.023		0.023		0.037	ns/pF
${\sf d_{THLS}}^4$	Delta High to Low—low slew		0.057		0.06		0.071		0.086		0.117	ns/pF

Note:

1. All –3 speed grades have been discontinued.

2. Delays based on 35 pF loading.

3. The equivalent IO Attribute settings for 2.5 V LVCMOS is 2.5 V LVTTL in the software.

4. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = $(0.1 * V_{CCI} - 0.9 * V_{CCI})/(C_{load} * d_{T[LH|HL|HLS]})$ where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-34 • A54SX32A Timing Characteristics

(Worst-Case Commercial Conditions	V _{CCA} = 2.25 V, V _{CCI} = 4.75 V, T _J = 70°C)
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		-3 S	peed ¹	-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
5 V PCI Out	put Module Timing ²											
t _{DLH}	Data-to-Pad Low to High		2.1		2.4		2.8		3.2		4.5	ns
t _{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns
t _{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0	2.8		ns
t _{ENZH}	Enable-to-Pad, Z to H		2.1		2.4		2.8		3.2		4.5	ns
t _{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.8		3.2		3.6		4.2		5.9	ns
d_{TLH}^{3}	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF
d_{THL}^{3}	Delta High to Low		0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Out	put Module Timing ⁴											
t _{DLH}	Data-to-Pad Low to High		1.9		2.2		2.5		2.9		4.1	ns
t _{DHL}	Data-to-Pad High to Low		2.5		2.9		3.3		3.9		5.4	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		6.6		7.6		8.6		10.1		14.2	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns
t _{ENZH}	Enable-to-Pad, Z to H		1.9		2.2		2.5		2.9		4.1	ns
t _{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.5		2.9		3.3		3.9		5.4	ns
d _{TLH} ³	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF
d_{THL}^3	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF
d _{THLS} ³	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. All –3 speed grades have been discontinued.

2. Delays based on 50 pF loading.

3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = $(0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$ where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-36 • A54SX72A Timing Characteristics (Continued)

		-3 Sp	beed*	-2 S	peed	-1 S	peed	Std. 9	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t _{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.9		3.4		3.8		4.5		6.3	ns
t _{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{qcksw}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t _{QCKSW}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t _{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: *All –3 speed grades have been discontinued.

Table 2-40 A54SX72A Timing Characteristics

(Worst-Case Commercial	Conditions Var	- 2 25 V V	$30V T_{1} - 70^{\circ}C$
(worst-case commercial	Conditions VCCA -	- 2.23 v, v _{CCl} –	3.0 v, 1 = 70 C)

		-3 Sp	beed ¹	-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
3.3 V PCI O	utput Module Timing ²											
t _{DLH}	Data-to-Pad Low to High		2.3		2.7		3.0		3.6		5.0	ns
t _{DHL}	Data-to-Pad High to Low		2.5		2.9		3.2		3.8		5.3	ns
t _{ENZL}	Enable-to-Pad, Z to L		1.4		1.7		1.9		2.2		3.1	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.3		2.7		3.0		3.6		5.0	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.5		2.8		3.2		3.8		5.3	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.5		2.9		3.2		3.8		5.3	ns
d _{TLH} ³	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d _{THL} ³	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
3.3 V LVTTL	Output Module Timing ⁴											
t _{DLH}	Data-to-Pad Low to High		3.2		3.7		4.2		5.0		6.9	ns
t _{DHL}	Data-to-Pad High to Low		3.2		3.7		4.2		4.9		6.9	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		10.3		11.9		13.5		15.8		22.2	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.2		2.6		2.9		3.4		4.8	ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew		15.8		18.9		21.3		25.4		34.9	ns
t _{ENZH}	Enable-to-Pad, Z to H		3.2		3.7		4.2		5.0		6.9	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.9		3.3		3.7		4.4		6.2	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.2		3.7		4.2		4.9		6.9	ns
d _{TLH} ³	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d _{THL} ³	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
d _{THLS} ³	Delta High to Low—low slew		0.053		0.053		0.067		0.073		0.107	ns/pF

Notes:

1. All –3 speed grades have been discontinued.

2. Delays based on 10 pF loading and 25 Ω resistance.

3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = $(0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$ where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-41 • A54SX72A Timing Characteristics

(Worst-Case Commercial Conditions	$V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_{J} = 70^{\circ}C$
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		-3 Sp	beed ¹	-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
5 V PCI Out	put Module Timing ²									•		
t _{DLH}	Data-to-Pad Low to High		2.7		3.1		3.5		4.1		5.7	ns
t _{DHL}	Data-to-Pad High to Low		3.4		3.9		4.4		5.1		7.2	ns
t _{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0) 2.8		ns
t _{ENZH}	Enable-to-Pad, Z to H		2.7		3.1		3.5		4.1		5.7	ns
t _{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.4		3.9		4.4		5.1		7.2	ns
d _{TLH} ³	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF
d _{THL} ³	Delta High to Low		0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Out	put Module Timing ⁴	•								•		
t _{DLH}	Data-to-Pad Low to High		2.4		2.8		3.1		3.7		5.1	ns
t _{DHL}	Data-to-Pad High to Low		3.1		3.5		4.0		4.7		6.6	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		7.4		8.5		9.7		11.4		15.9	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.1		3.7		5.1	ns
t _{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.1		3.5		4.0		4.7		6.6	ns
d _{TLH} ³	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF
d_{THL}^{3}	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF
d _{THLS} ³	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. All –3 speed grades have been discontinued.

2. Delays based on 50 pF loading.

3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = $(0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$ where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

	2	08-Pin PQF	P			2	08-Pin PQF	P	
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function	Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
1	GND	GND	GND	GND	36	I/O	I/O	I/O	I/O
2	TDI, I/O	TDI, I/O	tdi, I/o	TDI, I/O	37	I/O	I/O	I/O	I/O
3	I/O	I/O	I/O	I/O	38	I/O	I/O	I/O	I/O
4	NC	I/O	I/O	I/O	39	NC	ΙΟ	I/O	I/O
5	I/O	I/O	I/O	I/O	40	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
6	NC	I/O	I/O	I/O	41	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
7	I/O	I/O	I/O	I/O	42	I/O	I/O	I/O	I/O
8	I/O	I/O	I/O	I/O	43	I/O	I/O	I/O	I/O
9	I/O	I/O	I/O	I/O	44	I/O	I/O	I/O	I/O
10	I/O	I/O	I/O	I/O	45	I/O	I/O	I/O	I/O
11	TMS	TMS	TMS	TMS	46	I/O	I/O	I/O	I/O
12	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}	47	I/O	I/O	I/O	I/O
13	I/O	I/O	I/O	I/O	48	NC	I/O	I/O	I/O
14	NC	I/O	I/O	I/O	49	I/O	I/O	I/O	I/O
15	I/O	I/O	I/O	I/O	50	NC	ΙΟ	I/O	I/O
16	I/O	I/O	I/O	I/O	51	I/O	I/O	I/O	I/O
17	NC	I/O	I/O	I/O	52	GND	GND	GND	GND
18	I/O	I/O	I/O	GND	53	I/O	I/O	I/O	I/O
19	I/O	I/O	I/O	V _{CCA}	54	I/O	I/O	I/O	I/O
20	NC	I/O	I/O	I/O	55	I/O	I/O	I/O	I/O
21	I/O	I/O	I/O	I/O	56	I/O	I/O	I/O	I/O
22	I/O	I/O	I/O	I/O	57	I/O	I/O	I/O	I/O
23	NC	I/O	I/O	I/O	58	I/O	I/O	I/O	I/O
24	I/O	I/O	I/O	I/O	59	I/O	I/O	I/O	I/O
25	NC	NC	NC	I/O	60	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
26	GND	GND	GND	GND	61	NC	I/O	I/O	I/O
27	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}	62	I/O	I/O	I/O	I/O
28	GND	GND	GND	GND	63	I/O	I/O	I/O	I/O
29	I/O	I/O	I/O	I/O	64	NC	I/O	I/O	I/O
30	TRST, I/O	trst, I/O	trst, I/O	TRST, I/O	65	I/O	I/O	NC	I/O
31	NC	I/O	I/O	I/O	66	I/O	I/O	I/O	I/O
32	I/O	I/O	I/O	I/O	67	NC	I/O	I/O	I/O
33	I/O	I/O	I/O	I/O	68	I/O	I/O	I/O	I/O
34	I/O	I/O	I/O	I/O	69	I/O	I/O	I/O	I/O
35	NC	I/O	I/O	I/O	70	NC	I/O	I/O	I/O



176-Pin TQFP

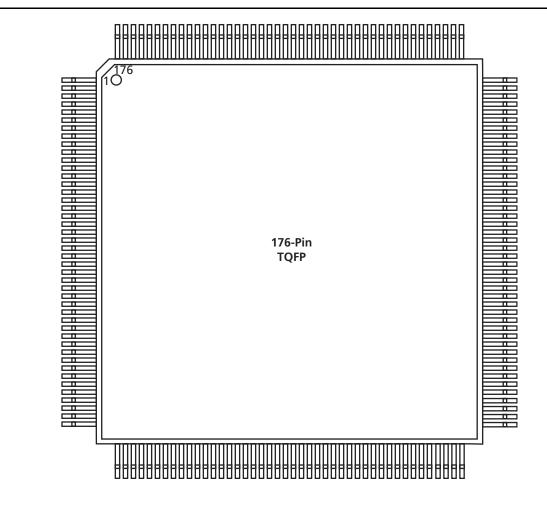


Figure 3-4 • 176-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.



256-Pin FBGA										
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function							
P15	I/O	I/O	I/O							
P16	I/O	I/O	I/O							
R1	I/O	I/O	I/O							
R2	GND	GND	GND							
R3	I/O	I/O	I/O							
R4	NC	I/O	I/O							
R5	I/O	I/O	I/O							
R6	I/O	I/O	I/O							
R7	I/O	I/O	I/O							
R8	I/O	I/O	I/O							
R9	HCLK	HCLK	HCLK							
R10	I/O	I/O	QCLKB							
R11	I/O	I/O	I/O							
R12	I/O	I/O	I/O							
R13	I/O	I/O	I/O							
R14	I/O	I/O	I/O							
R15	GND	GND	GND							
R16	GND	GND	GND							
T1	GND	GND	GND							
T2	I/O	I/O	I/O							
T3	I/O	I/O	I/O							
T4	NC	I/O	I/O							
T5	I/O	I/O	I/O							
T6	I/O	I/O	I/O							
T7	I/O	I/O	I/O							
T8	I/O	I/O	I/O							
Т9	V _{CCA}	V _{CCA}	V _{CCA}							
T10	I/O	I/O	I/O							
T11	I/O	I/O	I/O							
T12	NC	I/O	I/O							
T13	I/O	I/O	I/O							
T14	I/O	I/O	I/O							
T15	TDO, I/O	TDO, I/O	TDO, I/O							
T16	GND	GND	GND							

484-Pin FBGA

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Figure 3-8 • 484-Pin FBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.